Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/541,759	MIYAO ET AL.	
Examiner	Art Unit	
Hae M. Hyeon	2839	

SEARCHED				
Class	Subclass	Date	Examiner	
Search	Updated	6/61	hmh	
		:		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
385	70	6/01	hmh		
439	567	1	V		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Interference Text Search Done	6/01	hmh		
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